

INTERMETALLIC AND JOINT STRENGTH STUDY OF Sn-9Zn SOLDER WITH ADDITION OF CARBON NANOTUBE UNDER LIQUID STATE AGING

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ABSTRACT

In this study, the effect of carbon nanotube (CNTs) on the intermetallic and joint strength study of Sn-9Zn lead free solder under liquid state aging was investigated. The formations of intermetallic were observed under scanning electron microscopy (SEM) and the thicknesses of the intermetallic were measured by using imageJ software. Only Cu_5Zn_8 layer was found for Sn-9Zn/Cu interface. Meanwhile, there was three type of intermetallic formed for Sn-9Zn-0.1CNT/Cu interface which were Cu_5Zn_8 , Cu_3Sn and Cu_6Sn_5 . The thickness of intermetallic increased as the time of aging increases. However, the thickness of intermetallic formed with the addition of CNT was slightly smaller than those solder without the CNT. The joint strength of the Sn-9Zn solder was higher compared to Sn-9Zn-0.1CNT.

Keywords: Cu_5Zn_8 Intermetallic; Lead-free Solder; Sn-9Zn Solder; Joint Strength

INTRODUCTION

Sn-Pb solder is the most widely used solder in the interconnection electronics assembly. Nevertheless, Environmental Protection Agency (EPA) has cited lead and Pb compounds as one of the top 17 chemical posing the greatest threat to human life and the environment [1]. Hereby the advents of lead-free solders were proposed. Although there are many potential lead-free solders, Sn-9Zn solder is one of the most recommended solder due to its low (198°C) melting temperature. The mechanical property of the Sn-9Zn was improved by adding third element into it [2]. During soldering, the solder material will react with the Cu substrate and forming interface termed intermetallic compound (IMC). In the Sn-Zn system, both Sn and Zn interact with Cu to form intermetallic such as Cu_5Zn_8 , Cu_6Sn_5 and Cu_3Sn [3]. The formation of the intermetallic compounds between solder and Cu substrate is desirable for the good formation of the solder joint and play a crucial role in the reliability of solder joints. However, too thick of intermetallic and the brittleness of the intermetallic layer may be detrimental to joint reliability. This study investigated the effect of carbon nanotube (CNTs) on the intermetallic and joint strength study of Sn-9Zn lead free solder under liquid state aging.

METHODOLOGY

Solder/copper joint were made by reflowing around 0.5g of solder on Cu substrate with some ZnCl_2 flux were placed on the hot plate and heated at temperature 250°C . The soldering time were set at 1, 30, 45 and 60 minutes.

After the soldering and left to be cool, the samples were cleaned using soap and were cross- sectioned by using 8" sheet metal shear steel aluminum copper hand cutter. The samples were then mounted using epoxy resin. The mounted samples were mirror polished and etched by 93 vol % $\text{C}_2\text{H}_5\text{OH}$, 5 vol % HNO_3 and 2 vol % HCl . The Cu/solder interface was then analyzed under scanning electron Microscope (SEM) and the average thickness of IMC was calculated by using imageJ 1.46r software. For each sample, 3 micrographs were taken. To determine the joint strength of the solder/Cu, the two ends of the Cu was pulled using Instron machine, the stress and strain were then measured. There is no specific standard since we are comparing the joint strength.

RESULT AND DISCUSSION

Intermetallic formation

Figure 1 and 2 shows the intermetallic formation after soldering for 1 and 45 minutes at 250°C . As reported [4-5], by using thermodynamic calculation the Cu_5Zn_8 was the first of the intermetallic formed at the Sn-9Zn/Cu interface. The Zn concentrates at the interface close to the Cu substrate and reacts with Cu to form the Cu_5Zn_8 . In figure 1(a) and (b), the morphology of the Cu_5Zn_8 intermetallic planar-shape formed with both Sn-9Zn/Cu interface and Sn-9Zn-0.1CNT/Cu interface.

Figure 2(a) shows the formation of Cu_5Zn_8 intermetallic after soldering for 45 minute at 250°C . The thickness of intermetallic was increases. The scallop-shaped Cu_6Sn_5 and planar-shaped Cu_3Sn intermetallic layers were formed at the Sn-9Zn-0.1CNT/Cu interface after soldering at 250°C for 45 minutes, as shown in figure 2(b). The Cu_6Sn_5 colour is light grey meanwhile the Cu_3Sn colour is darker. According to the Chang *et al.* [6], this is due to the fact that the Cu atoms in the Cu_5Zn_8 layer diffuse to the solder alloy and then react with Sn. Wang *et al.* [7] reported that the Cu_6Sn_5 and Cu_3Sn phases could form at the Sn-9Zn/Cu interface after aging at higher temperature due to phase fracture of Cu_5Zn_8 . At longer time aging, the CNT may have retarded the diffusion of Zn atoms. These allow the diffusion of Sn atoms towards Cu to form the Cu_6Sn_5 and Cu_3Sn intermetallic.

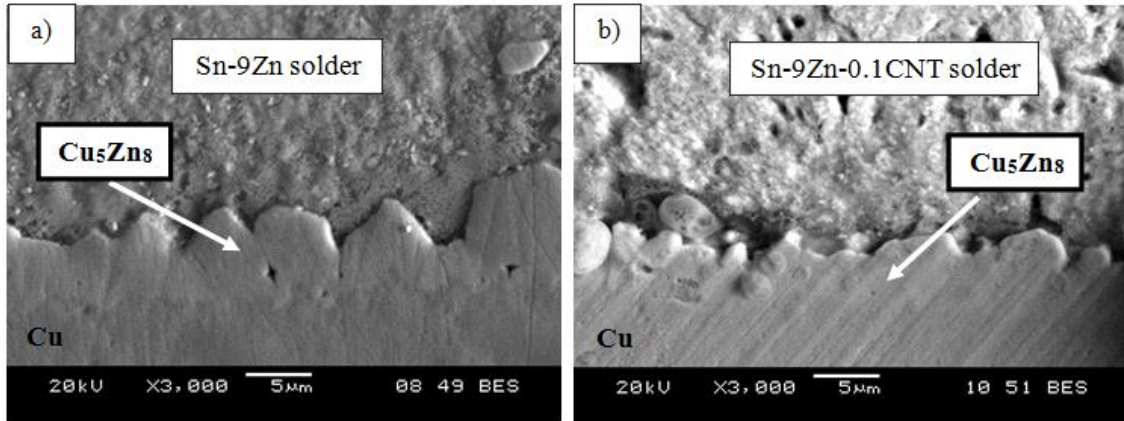


Figure 1: IMC formation of (a) Sn-9Zn, (b) Sn-9Zn-0.1CNT at 1 minute aging time under SEM

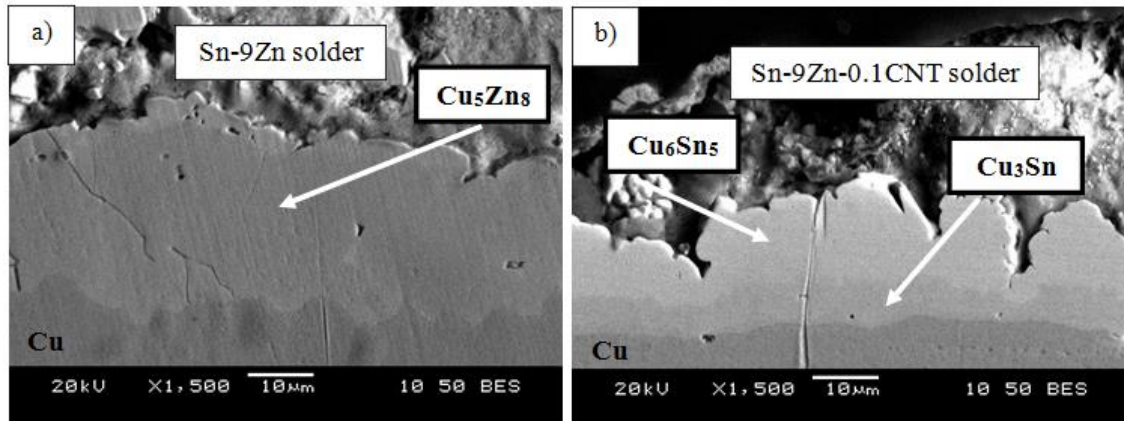


Figure 2: IMC formation of (a) Sn-9Zn, (b) Sn-9Zn-0.1CNT at 45 minute time aging under SEM

Intermetallic thickness formation

When soldering was done at 250°C for 1 minute, the Cu_5Zn_8 intermetallic for Sn-9Zn/Cu and Sn-9Zn-0.1CNT/Cu have thickness around 7μm and 5μm. This intermetallic thickness increases as the aging time increases as shown in figure 3 and 4. A few studies [8-9] reported that the thickness of Cu_5Zn_8 increases as the time of soldering increases for liquid state aging for Sn-9Zn/Cu system. The present results clearly show that the addition of CNT in the Sn-9Zn solder retarded the growth of intermetallic. Figure 5 shows the bar chart intermetallic thickness vs time for both solders.

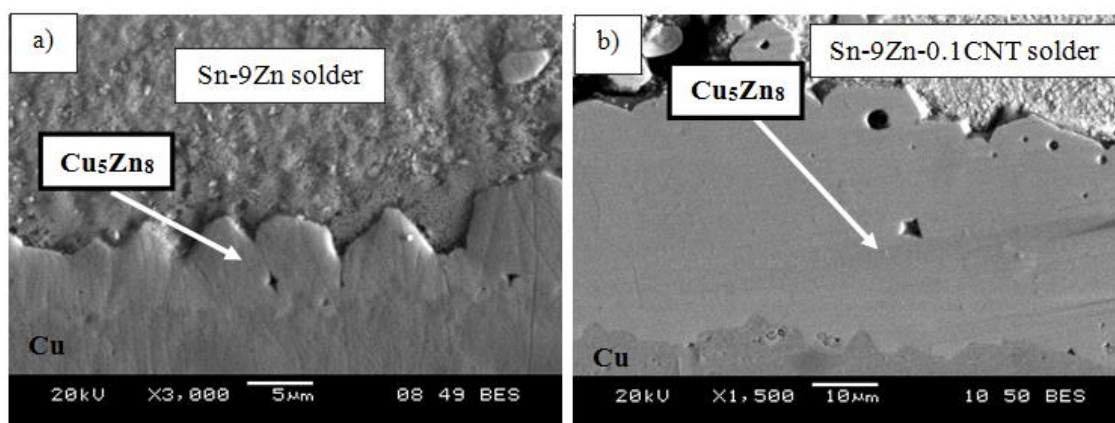


Figure 3: IMC formation soldering at Sn-9Zn/Cu interface for (a) 1 and (b) 60 minutes

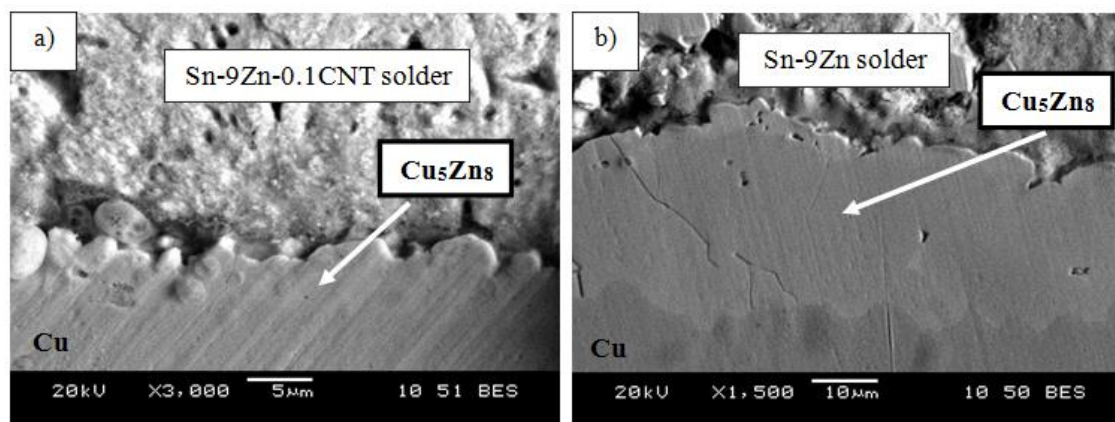


Figure 4: IMC formation soldering at Sn-9Zn-0.1CNT/Cu interface for (a) 1 and (b) 60 minutes

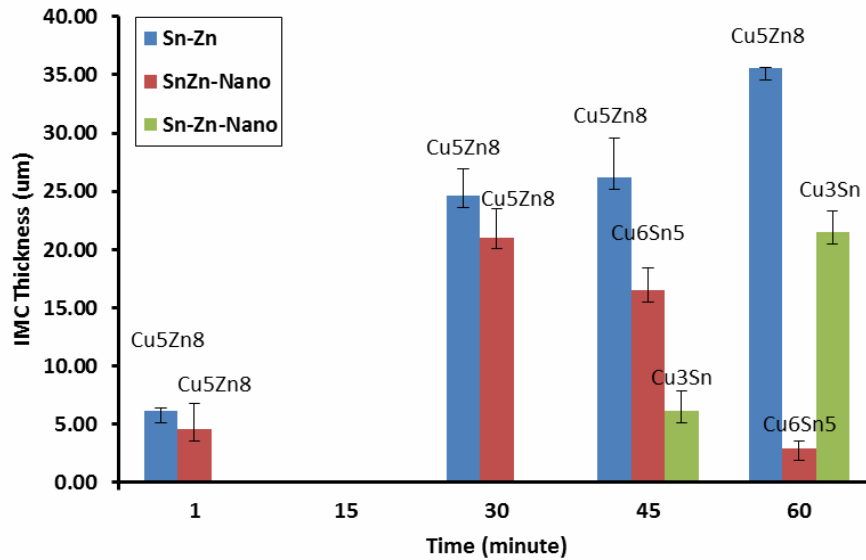


Figure 5: Bar chart IMC thickness vs Time

Joint strength

Figure 6 shows stress at maximum of solders which decreases as time of aging increases. According to Ahat et al. [10], as the intermetallic increases it will cause the strength of the solder joint decreases. The strength of Sn-9Zn solder is higher than the Sn-9Zn-0.1CNT. Meanwhile, figure 7 show strain at break of solders which increases as time of aging increases from 1 to 30 minutes. Then the strain reading decreases after aging for 45 minutes and increases when time is raised until 60 minutes. The strain of Sn-9Zn solder is higher than the Sn-9Zn-0.1CNT. The results for both stress at maximum and strain at break of the solders are summarized in tables 1 and 2.

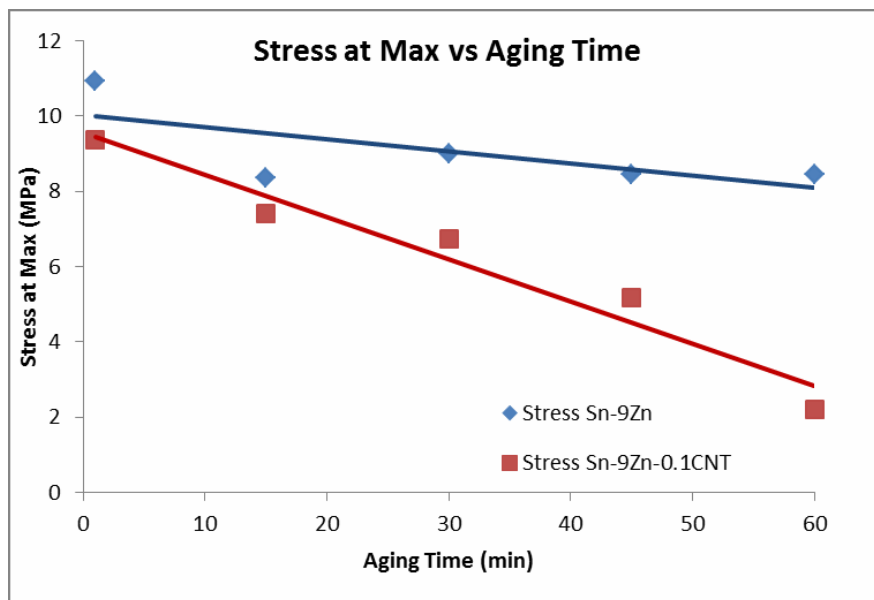


Figure 6: Graph Stress at Max vs Aging Time

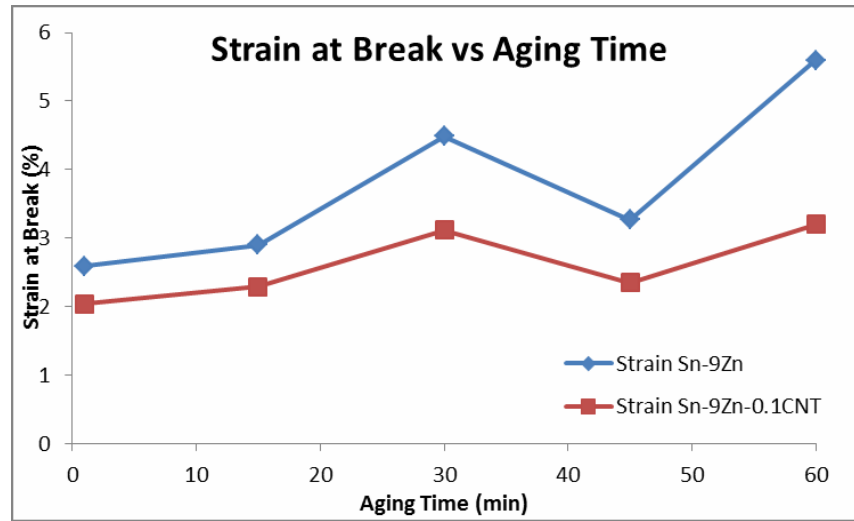


Figure 7: Graph Strain at Break vs Aging Time

Table 1: Stress at maximum for joint strength test

Aging Time [minute]	Stress at Max [MPa]	
	Sn-9Zn/Cu	Sn-9Zn-0.1CNT/Cu
1	10.93	9.37
15	8.37	7.4
30	9.00	6.75
45	8.47	5.17
60	8.47	2.20

Table 2: Strain at break for joint strength test

Aging Time (minute)	Strain at Break (%)	
	Sn-9Zn/Cu	Sn-9Zn-0.1CNT/Cu
1	2.59	2.04
15	2.90	2.29
30	4.49	3.11
45	3.27	2.35
60	5.60	3.20

CONCLUSION

The formation of the thickness of the intermetallic was investigated including the joint strength properties of those solder. The formations of the Cu_5Zn_8 were observed at the Sn-9Zn/Cu interface and thickness of IMC was increased as the aging time increased. Meanwhile, the formations of two layers of Cu_6Sn_5 and Cu_3Sn demonstrated on the Sn-9Zn-0.1CNT/Cu interface after soldering for 45 and 60 minutes. Based on the results, the thickness of the intermetallic layer of Sn-9Zn- 0.1CNT/Cu interface was smaller compared to thickness of intermetallic layer for Sn-9Zn/Cu interface. This indicated that the presence of the CNT in the Sn-9Zn solder acted as effective retarding agent. However, the joint strength properties were observed to decrease with addition of CNT in the Sn-9Zn solder. The stress strength of the solder decreased with the increased of the aging time.

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